

FDP19N40 N-Channel UniFETTM MOSFET 400 V, 19 A, 240 mΩ

Features

- $R_{DS(on)}$ = 200 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 9.5 A
- Low Gate Charge (Typ. 32 nC)
- Low C_{rss} (Typ. 20 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- RoHS Compliant

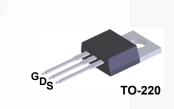
Applications

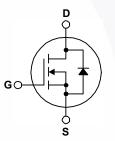
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

November 2013

Description

UniFETTM MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on-state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

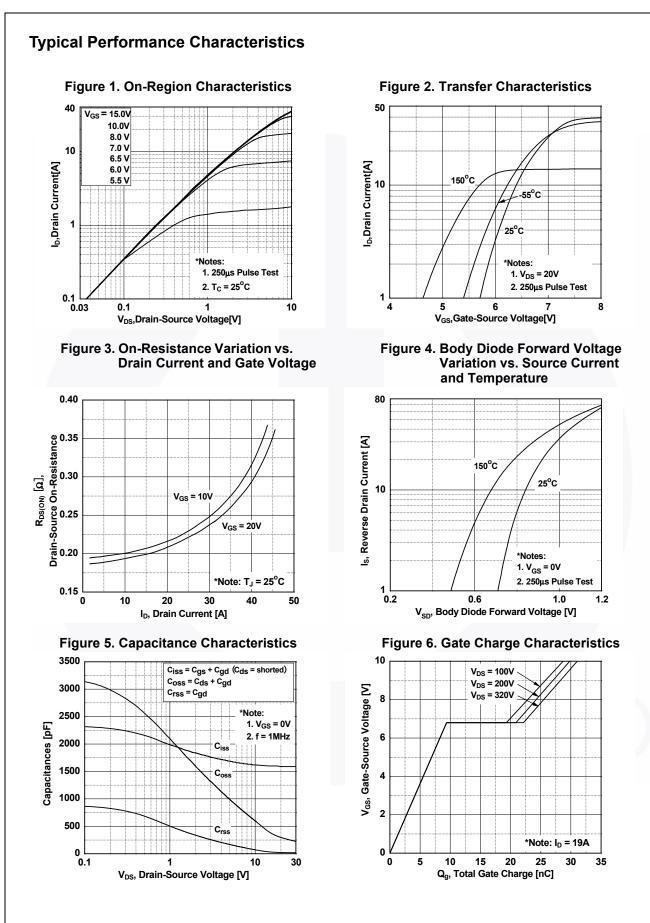
| Symbol | | Parameter | | FDP19N40 | Unit | |
|-----------------------------------|--|--|-------------|-------------|------|--|
| V _{DSS} | Drain to Source Voltage | | | 400 | V | |
| V _{GSS} | Gate to Source Voltage | | ±30 | V | | |
| I _D C | Drain Current | - Continuous (T _C = 25 ^o C) | | 19 | А | |
| | Drain Current | - Continuous (T _C = 100 ^o C) | | 11.4 | — A | |
| I _{DM} | Drain Current | - Pulsed | (Note 1) | 76 | A | |
| E _{AS} | Single Pulsed Avalanche Energy (Note 2) | | (Note 2) | 542 | mJ | |
| I _{AR} | Avalanche Current (Note 1 | | (Note 1) | 19 | Α | |
| E _{AR} | Repetitive Avalanche Energy (Note 1) | | (Note 1) | 21.5 | mJ | |
| dv/dt | Peak Diode Recovery du | //dt | (Note 3) | 15 | V/ns | |
| P _D | Power Dissipation | (T _C = 25 ^o C) | | 215 | W | |
| | | - Derate Above 25°C | | 1.65 | W/ºC | |
| T _J , T _{STG} | Operating and Storage Temperature Range | | | -55 to +150 | °C | |
| TL | Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds | | r 5 Seconds | 300 | °C | |

Thermal Characteristics

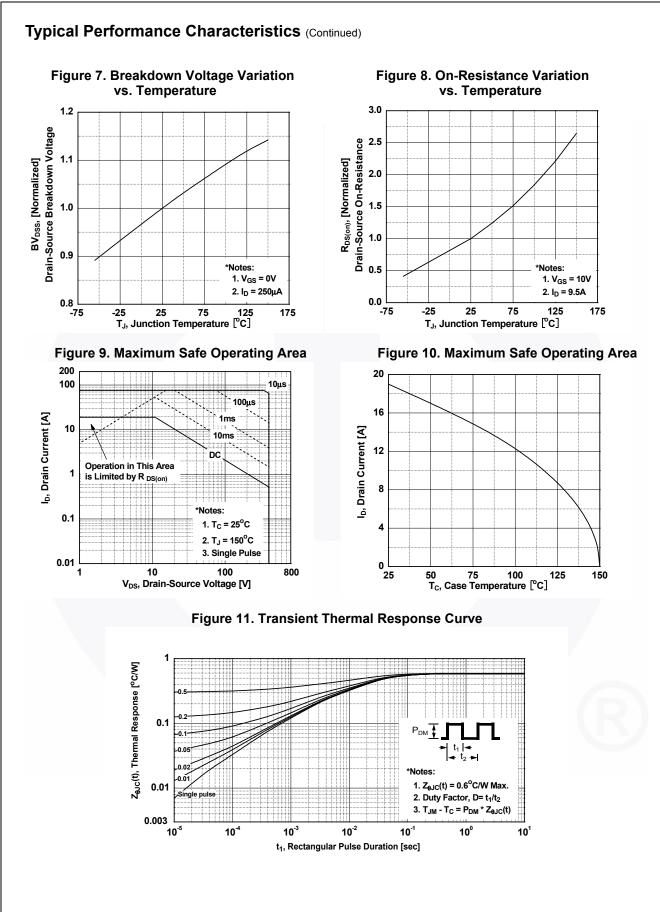
| Symbol | Parameter | FDP19N40 | Unit |
|-----------------|---|----------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case, Max. | 0.6 | °C/W |
| R_{\thetaJA} | Thermal Resistance, Junction to Ambient, Max. | 62.5 | 0/00 |

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| 0 FDP19N40 Characteristics T _C = 2 Parameter ristics | TO-2 25°C unless | s otherwise no | Tube oted. est Condition | N/A | | N/A | 50 | units |
|--|---|--|--|--|---|---|--|--|
| Parameter | 25°C unless | | | | | | | |
| Parameter | _ | | | | | | | |
| ristics | | | st contaition | IS | Min. | Тур. | Max. | Unit |
| | | | | | | | | |
| Prain to Source Breakdown Volt | age | I _D = 250 μA | , V _{GS} = 0 V, ⁻ | Г. ₁ = 25 ^о С | 400 | - | - | V |
| reakdown Voltage Temperature | | $I_D = 250 \ \mu\text{A}$, Referenced to 25°C | | - | 0.5 | - | V/ºC | |
| Zero Gate Voltage Drain Current | | | | | - | - | 1 | μA |
| | | | | , | | | | nA |
| | | •63 200 | ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,, | | | | 1100 | |
| ristics | | | | | | | | T |
| Sate Threshold Voltage | | | | | 3.0 | - | 5.0 | V |
| | tance | 00 | 5 | | - | - | 0.24 | Ω |
| orward Transconductance | | V _{DS} = 20 V, | I _D = 9.5 A | | - | 18.3 | | S |
| aracteristics | | | | | | | | |
| nput Capacitance | | | | | - | 1590 | 2115 | pF |
| Output Capacitance | | V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz | | | - | 255 | 340 | pF |
| everse Transfer Capacitance | | | | - | 20 | 29 | pF | |
| otal Gate Charge at 10V | | V _{DS} = 320 V | /, I _D = 19 A, | | - | 32 | 40 | nC |
| Sate to Source Gate Charge | | V _{GS} = 10 V | | - | 10 | - | nC | |
| Sate to Drain "Miller" Charge | | | | (Note 4) | - | 13 | - | nC |
| naracteristics | | | | | | | | |
| urn-On Delay Time | | | | | - | 31 | 72 | ns |
| urn-On Rise Time | | V _{DD} = 200 V, I _D = 19 A, | | - | 70 | 150 | ns | |
| urn-Off Delay Time | | V _{GS} = 10 V, | $R_{G} = 25 \Omega$ | | - | 82 | 174 | ns |
| urn-Off Fall Time | | | | (Note 4) | · · / | 49 | 108 | ns |
| Diode Characteristics | | | | | | | | |
| laximum Continuous Drain to S | ource Diod | e Forward Cu | rrent | | 7 - | - | 19 | Α |
| | | | | | - | - | 76 | Α |
| rain to Source Diode Forward | /oltage | V _{GS} = 0 V, I | _{SD} = 19 A | | - | - | 1.4 | V |
| everse Recovery Time | | V _{GS} = 0 V, I _{SD} = 19 A, | | | - | 349 | | ns |
| everse Recovery Charge | | $dI_F/dt = 100$ | A/μs | | - | 3.56 | - | μC |
| | coefficient ero Gate Voltage Drain Curren Gate to Body Leakage Current ristics Gate Threshold Voltage Static Drain to Source On Resis forward Transconductance tracteristics oput Capacitance put Capacitance output Capacitance teverse Transfer Capacitance otal Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge tracteristics urn-On Delay Time urn-On Rise Time urn-Off Fall Time Diode Characteristics aximum Continuous Drain to S aximum Pulsed Drain to Source rain to Source Diode Forward V everse Recovery Time everse Recovery Charge | Bioefficient ero Gate Voltage Drain Current Gate to Body Leakage Current ristics Gate Threshold Voltage Bate to Characteristics Bate to Drain "Miller" Charge Bate to Drain Time urn-On Delay Time urn-Off Fall Time Diode Characteristics aximum Continuous Drain to Source Diode Formard Voltage everse Recovery Time | coefficientID $250 \ \mu A$ ero Gate Voltage Drain Current $V_{DS} = 400 \ V_{DS} = 320 \ V_{DS} = 320 \ V_{DS} = 320 \ V_{CS} = 320 \ V_{CS} = 320 \ V_{CS} = 10 \ V_{CS} = 20 \ V_{CS} = 10 \ V_{CS$ | coefficientID= 250 μ A, Referencedero Gate Voltage Drain Current $V_{DS} = 400 \vee, V_{GS} = 0 \vee$ Gate to Body Leakage Current $V_{GS} = 400 \vee, V_{GS} = 0 \vee$ risticsVGate Threshold Voltage $V_{GS} = \pm 30 \vee, V_{DS} = 0 \vee$ risticsSate Threshold Voltage $V_{GS} = \pm 30 \vee, V_{DS} = 0 \vee$ risticsSate Threshold Voltage $V_{GS} = 10 \vee, I_D = 9.5 \Lambda$ convard Transconductance $V_{DS} = 20 \vee, I_D = 9.5 \Lambda$ reverse Transfer Capacitance $V_{DS} = 25 \vee, V_{GS} = 0 \vee, f = 1 MHz$ reverse Transfer Capacitance $V_{DS} = 320 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee$ reverse Transfer Capacitance $V_{DS} = 320 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee$ reacteristics $V_{DD} = 200 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee, I_D = 200 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee, I_D = 200 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee, I_D = 25 \Omega$ run-On Delay Time $V_{DD} = 200 \vee, I_D = 19 \Lambda, V_{GS} = 10 \vee, R_G = 25 \Omega$ run-Off Delay Time $V_{CS} = 0 \vee, I_S = 19 \Lambda, V_{GS} = 0 \vee, I_S = 19 \Lambda, V_{$ | coefficientID= 250 µA, Referenced to 25°Cero Gate Voltage Drain Current $V_{DS} = 400 V, V_{GS} = 0 V$ Sate to Body Leakage Current $V_{GS} = 320 V, T_C = 125°C$ Sate to Body Leakage Current $V_{GS} = 320 V, V_{DS} = 0 V$ risticsSate Threshold Voltage $V_{GS} = 10 V, I_D = 9.5 A$ Sate Threshold Voltage $V_{GS} = 10 V, I_D = 9.5 A$ static Drain to Source On Resistance $V_{DS} = 20 V, I_D = 9.5 A$ static Drain to Source On Resistance $V_{DS} = 25 V, V_{GS} = 0 V, I_D = 9.5 A$ state to Body Leakage at 10V $V_{DS} = 25 V, V_{GS} = 0 V, I_D = 9.5 A$ state to Charge at 10V $V_{DS} = 320 V, I_D = 19 A, V_{GS} = 10 V$ state to Source Gate Charge $V_{DS} = 320 V, I_D = 19 A, V_{GS} = 10 V$ state to Drain "Miller" Charge $V_{DD} = 200 V, I_D = 19 A, V_{GS} = 10 V, R_G = 25 \Omega$ urn-On Delay Time $V_{DD} = 200 V, I_D = 19 A, V_{GS} = 10 V, R_G = 25 \Omega$ urn-Off Delay Time $V_{DD} = 200 V, I_D = 19 A, V_{GS} = 10 V, R_G = 25 \Omega$ urn-Off Fall Time $V_{DS} = 10 V, R_G = 25 \Omega$ stimum Continuous Drain to Source Diode Forward Currentaximum Pulsed Drain to Source Diode Forward Currentrain to Source Diode Forward Voltage $V_{GS} = 0 V, I_{SD} = 19 A, V_{GS} = 0 V, I_{SD} = 19 A, V_{SS} = 0$ | coefficientID= 250 μ A, Referenced to 25°C-ero Gate Voltage Drain Current $V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}$ -Sate to Body Leakage Current $V_{GS} = 430 \text{ V}, V_{DS} = 0 \text{ V}$ -risticsSate Threshold Voltage $V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$ -risticsSate Threshold Voltage $V_{GS} = 10 \text{ V}, I_D = 9.5 \text{ A}$ -forward Transconductance $V_{GS} = 20 \text{ V}, I_D = 9.5 \text{ A}$ -orward Transconductance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ -futput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ -futput Capacitance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ -take to Source Gate Charge $V_{DS} = 320 \text{ V}, I_D = 19 \text{ A},$ -valate to Source Gate Charge $V_{GS} = 10 \text{ V},$ -take to Drain "Miller" Charge $V_{DD} = 200 \text{ V}, I_D = 19 \text{ A},$ -urn-On Delay Time $V_{GS} = 10 \text{ V},$ urn-Off Delay Time $V_{GS} = 10 \text{ V},$ urn-Off Fall Time $V_{GS} = 00 \text{ V},$ urn-Off Fall Time $V_{GS} = 00 \text{ V},$ urn-Off Fall Time $V_{GS} = 00 \text{ V},$ urn-Off Fall Time $V_{GS} = 0 \text{ V},$ </td <td>coefficientID2.50 µA, Reference to 2.5°C-0.5ero Gate Voltage Drain Current$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}$Sate to Body Leakage Current$V_{GS} = 400 \text{ V}, V_{DS} = 0 \text{ V}$sate to Body Leakage Current$V_{GS} = 125^{\circ}$CristicsSate Threshold Voltage$V_{GS} = V_{DS}, I_D = 250 \mu$A3.0risticsSate Threshold Voltage$V_{GS} = V_{DS}, I_D = 250 \mu$A3.0risticsSate Threshold Voltage$V_{GS} = 10 \text{ V}, I_D = 9.5 \text{ A}$-0.2forward Transconductance$V_{DS} = 25 \text{ V}, 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Current $V_{GS} = 400 \text{ V}, V_{DS} = 0 \text{ V}$ sate to Body Leakage Current $V_{GS} = 125^{\circ}$ CristicsSate Threshold Voltage $V_{GS} = V_{DS}, I_D = 250 \mu$ A3.0risticsSate Threshold Voltage $V_{GS} = V_{DS}, I_D = 250 \mu$ A3.0risticsSate Threshold Voltage $V_{GS} = 10 \text{ V}, I_D = 9.5 \text{ A}$ -0.2forward Transconductance $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 9.5 \text{ A}$ -18.3racteristicsput Capacitance $V_{DS} = 25 \text{ V}, V_{CS} = 0 \text{ V}, I_D = 9.5 \text{ A}$ -1590otal Gate Charge at 10V $V_{DS} = 320 \text{ V}, I_D = 19 \text{ A}, V_{GS} = 10 \text{ V}$ -32value to Source Gate Charge $V_{GS} = 10 \text{ V}, I_D = 19 \text{ A}, V_{CS} = 10 \text{ V}$ -10value to Drain "Miller" Charge $V_{DD} = 200 \text{ V}, I_D = 19 \text{ A}, V_{CS} = 10 \text{ V}$ -31urn-On Delay Time $V_{DS} = 10 \text{ V}, R_G = 25 \Omega$ -82urn-Off Fall Time $V_{CS} = 0 \text{ V}, I_S = 19 \text{ A},32urn-Off Fall TimeV_{GS} = 0 \text{ V}, I_S = 19 \text{ A},verse 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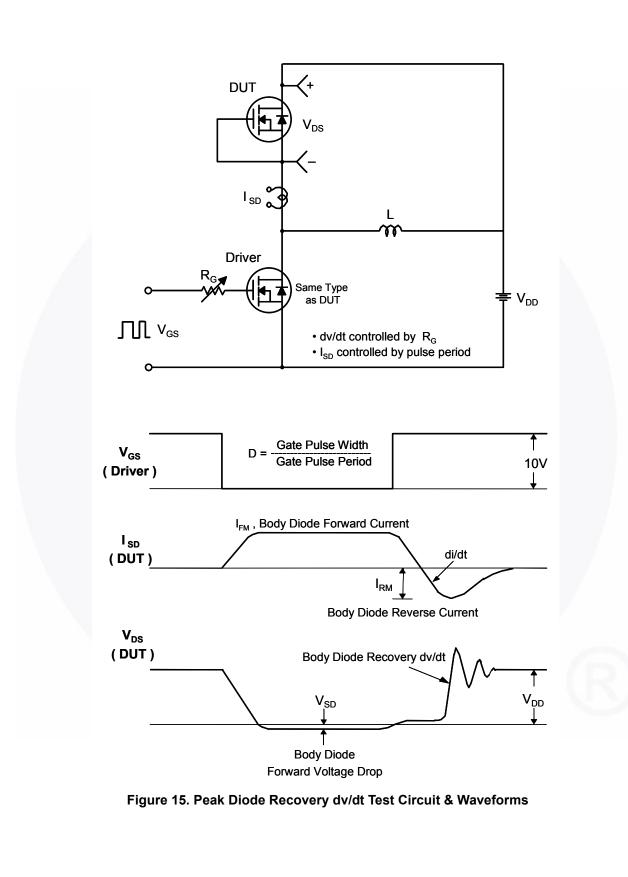


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 V_{GS} ξ א Q_g FV_{DS} Q_{gd} Q_{gs} • DUT I_G = const. Charge Figure 12. Gate Charge Test Circuit & Waveform R VDS V_{DS} 90% ο V_{DD} GS R_{G} 10% V_{GS} DUT V_{GS} ∏ 0 Figure 13. Resistive Switching Test Circuit & Waveforms L $E_{AS} = \frac{1}{2} L I_{AS}^2$ V_{DS} $\mathsf{BV}_{\mathsf{DSS}}$ ID o I_{AS} R_{G} ŧν_{DD} $I_{D}(t)$ V_{GS}] $V_{DS}(t)$ V_{DD} DUT Time t_p Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

FDP19N40 — N-Channel UniFETTM MOSFET



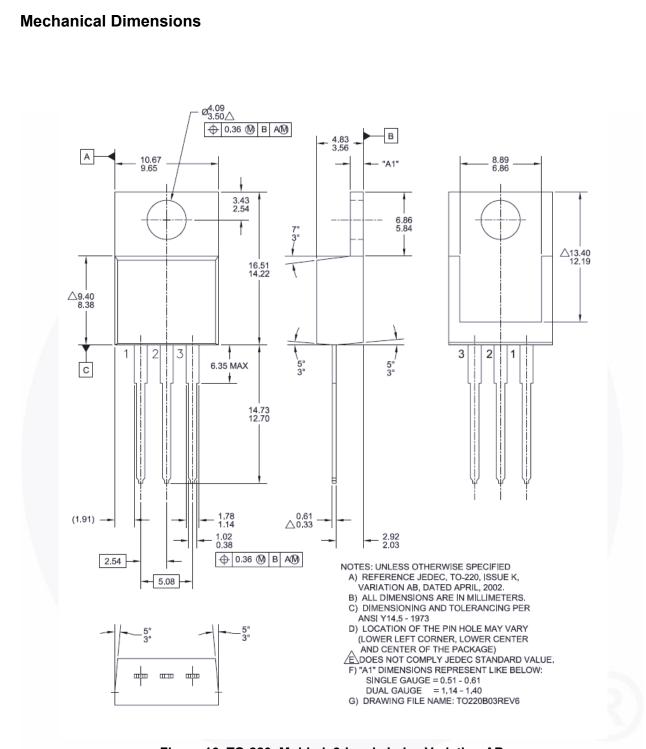


Figure 16. TO-220, Molded, 3-Lead, Jedec Variation AB

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